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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	4075
Number of Logic Elements/Cells	52160
Total RAM Bits	2764800
Number of I/O	210
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (Tj)
Package / Case	324-LFBGA, CSPBGA
Supplier Device Package	324-CSPBGA (15x15)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc7a50t-2csg324i

Table 3: DC Characteristics Over Recommended Operating Conditions (Cont'd)

Symbol	Description	Min	Typ ⁽¹⁾	Max	Units
n	Temperature diode ideality factor	—	1.010	—	—
r	Temperature diode series resistance	—	2	—	Ω

Notes:

1. Typical values are specified at nominal voltage, 25°C.
2. This measurement represents the die capacitance at the pad, not including the package.
3. Maximum value specified for worst case process at 25°C.
4. Termination resistance to a V_{CCO}/2 level.

Table 4: V_{IN} Maximum Allowed AC Voltage Overshoot and Undershoot for 3.3V HR I/O Banks⁽¹⁾

AC Voltage Overshoot	% of UI @-40°C to 100°C	AC Voltage Undershoot	% of UI @-40°C to 100°C
V _{CCO} + 0.40	100	-0.40	100
V _{CCO} + 0.45	100	-0.45	61.7
V _{CCO} + 0.50	100	-0.50	25.8
V _{CCO} + 0.55	100	-0.55	11.0
V _{CCO} + 0.60	46.6	-0.60	4.77
V _{CCO} + 0.65	21.2	-0.65	2.10
V _{CCO} + 0.70	9.75	-0.70	0.94
V _{CCO} + 0.75	4.55	-0.75	0.43
V _{CCO} + 0.80	2.15	-0.80	0.20
V _{CCO} + 0.85	1.02	-0.85	0.09
V _{CCO} + 0.90	0.49	-0.90	0.04
V _{CCO} + 0.95	0.24	-0.95	0.02

Notes:

1. A total of 200 mA per bank should not be exceeded.

Table 5: Typical Quiescent Supply Current

Symbol	Description	Device	Speed Grade				Units	
			1.0V		0.9V			
			-3	-2/-2L	-1	-2L		
I _{CCINTQ}	Quiescent V _{CCINT} supply current	XC7A100T	155	155	155	108	mA	
		XC7A200T	328	328	328	232	mA	
I _{CCOQ}	Quiescent V _{CCO} supply current	XC7A100T	4	4	4	4	mA	
		XC7A200T	5	5	5	5	mA	
I _{CCAUXQ}	Quiescent V _{CCAUX} supply current	XC7A100T	36	36	36	36	mA	
		XC7A200T	73	73	73	73	mA	
I _{CCBRAMQ}	Quiescent V _{CCBRAM} supply current	XC7A100T	4	4	4	4	mA	
		XC7A200T	11	11	11	11	mA	

Notes:

1. Typical values are specified at nominal voltage, 85°C junction temperature (T_j) with single-ended SelectIO resources.
2. Typical values are for blank configured devices with no output current loads, no active input pull-up resistors, all I/O pins are 3-state and floating.
3. Use the Xilinx Power Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate static power consumption for conditions other than those specified.

Table 6 shows the minimum current, in addition to I_{CCQ} , that is required by Artix-7 devices for proper power-on and configuration. If the current minimums shown in **Table 5** and **Table 6** are met, the device powers on after all four supplies have passed through their power-on reset threshold voltages. The FPGA must not be configured until after V_{CCINT} is applied.

Once initialized and configured, use the Xilinx Power Estimator (XPE) tools to estimate current drain on these supplies.

Table 6: Power-On Current for Artix-7 Devices⁽¹⁾

Device	$I_{CCINTMIN}$	$I_{CCAUXMIN}$	I_{CCOMIN}	$I_{CCBRAMMIN}$	Units
	Typ ⁽²⁾	Typ ⁽²⁾	Typ ⁽²⁾	Typ ⁽²⁾	
XC7A100T	$I_{CCINTQ} + 170$	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 60$	mA
XC7A200T	$I_{CCINTQ} + 340$	$I_{CCAUXQ} + 50$	$I_{CCOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 80$	mA

Notes:

1. Use the Xilinx Power Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate maximum power-on currents.
2. Typical values are specified at nominal voltage, 25°C.

Table 7: Power Supply Ramp Time

Symbol	Description	Conditions	Min	Max	Units
T_{VCCINT}	Ramp time from GND to 90% of V_{CCINT}		0.2	50	ms
T_{VCCO}	Ramp time from GND to 90% of V_{CCO}		0.2	50	ms
T_{VCCAUX}	Ramp time from GND to 90% of V_{CCAUX}		0.2	50	ms
$T_{VCCBRAM}$	Ramp time from GND to 90% of V_{CCBRAM}		0.2	50	ms
$T_{VCCO2VCCAUX}$	Allowed time per power cycle for $V_{CCO} - V_{CCAUX} > 2.625V$	$T_J = 100^{\circ}\text{C}^{(1)}$	—	500	ms
		$T_J = 85^{\circ}\text{C}^{(1)}$	—	800	
$T_{MGTAVCC}$	Ramp time from GND to 90% of $V_{MGTAVCC}$		0.2	50	ms
$T_{MGTAVTT}$	Ramp time from GND to 90% of $V_{MGTAVTT}$		0.2	50	ms

Notes:

1. Based on 240,000 power cycles with nominal V_{CCO} of 3.3V or 36,500 power cycles with worst case V_{CCO} of 3.465V.

LVDS DC Specifications (LVDS_25)

See [UG471: 7 Series FPGAs SelectIO Resources User Guide](#) for more information on the LVDS_25 standard in the HR I/O banks.

Table 11: LVDS_25 DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.375	2.500	2.625	V
V_{OH}	Output High Voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	–	–	1.675	V
V_{OL}	Output Low Voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	0.700	–	–	V
V_{ODIFF}	Differential Output Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High	$R_T = 100 \Omega$ across Q and \bar{Q} signals	247	350	600	mV
V_{OCM}	Output Common-Mode Voltage	$R_T = 100 \Omega$ across Q and \bar{Q} signals	1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High		100	350	600	mV
V_{ICM}	Input Common-Mode Voltage		0.300	1.200	1.425	V

AC Switching Characteristics

All values represented in this data sheet are based on the speed specifications in v1.07 from the 14.4/2012.4 device pack for ISE® Design Suite14.4 and Vivado® Design Suite 2012.4 for the -3, -2, -2L (1.0V), and -1 speed grades and v1.05 from the 14.4/2012.4 device pack for the -2L (0.9V) speed grade.

Switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

Advance Product Specification

These specifications are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

Preliminary Product Specification

These specifications are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

Production Product Specification

These specifications are released once enough production silicon of a particular device family member has been characterized to provide full correlation between specifications and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to Production before faster speed grades.

Testing of AC Switching Characteristics

Internal timing parameters are derived from measuring internal test patterns. All AC switching characteristics are representative of worst-case supply voltage and junction temperature conditions.

For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer and back-annotate to the simulation net list. Unless otherwise noted, values apply to all Artix-7 FPGAs.

Table 16: 3.3V IOB High Range (HR) Switching Characteristics (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units	
	Speed Grade				Speed Grade				Speed Grade					
	1.0V		0.9V		1.0V		0.9V		1.0V		0.9V			
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L		
LVCMOS15_F4	0.77	0.86	0.93	0.98	1.85	1.97	2.23	2.27	2.42	2.63	3.06	2.92	ns	
LVCMOS15_F8	0.77	0.86	0.93	0.98	1.60	1.72	1.98	2.21	2.17	2.38	2.81	2.86	ns	
LVCMOS15_F12	0.77	0.86	0.93	0.98	1.35	1.47	1.73	1.96	1.92	2.13	2.56	2.61	ns	
LVCMOS15_F16	0.77	0.86	0.93	0.98	1.34	1.46	1.71	1.94	1.90	2.12	2.54	2.59	ns	
LVCMOS12_S4	0.87	0.95	1.02	1.08	2.57	2.69	2.95	3.18	3.14	3.35	3.78	3.83	ns	
LVCMOS12_S8	0.87	0.95	1.02	1.08	2.09	2.21	2.46	2.69	2.65	2.87	3.29	3.34	ns	
LVCMOS12_S12	0.87	0.95	1.02	1.08	1.79	1.91	2.17	2.40	2.36	2.57	2.99	3.05	ns	
LVCMOS12_F4	0.87	0.95	1.02	1.08	1.98	2.10	2.35	2.58	2.54	2.76	3.18	3.23	ns	
LVCMOS12_F8	0.87	0.95	1.02	1.08	1.54	1.66	1.92	2.15	2.11	2.32	2.75	2.80	ns	
LVCMOS12_F12	0.87	0.95	1.02	1.08	1.38	1.51	1.76	1.97	1.95	2.16	2.59	2.62	ns	
SSTL135_S	0.67	0.75	0.82	0.87	1.35	1.47	1.73	1.93	1.92	2.13	2.56	2.58	ns	
SSTL15_S	0.60	0.68	0.75	0.80	1.30	1.43	1.68	1.88	1.87	2.09	2.51	2.53	ns	
SSTL18_I_S	0.67	0.75	0.82	0.87	1.67	1.79	2.04	2.24	2.23	2.45	2.87	2.89	ns	
SSTL18_II_S	0.67	0.75	0.82	0.87	1.31	1.43	1.68	1.91	1.87	2.09	2.51	2.56	ns	
DIFF_SSTL135_S	0.68	0.76	0.83	0.87	1.35	1.47	1.73	1.93	1.92	2.13	2.56	2.58	ns	
DIFF_SSTL15_S	0.68	0.76	0.83	0.87	1.30	1.43	1.68	1.88	1.87	2.09	2.51	2.53	ns	
DIFF_SSTL18_I_S	0.71	0.79	0.86	0.87	1.68	1.80	2.06	2.24	2.25	2.46	2.89	2.89	ns	
DIFF_SSTL18_II_S	0.71	0.79	0.86	0.87	1.38	1.51	1.76	1.94	1.95	2.17	2.59	2.59	ns	
SSTL135_F	0.67	0.75	0.82	0.87	1.12	1.24	1.49	1.71	1.69	1.90	2.32	2.36	ns	
SSTL15_F	0.60	0.68	0.75	0.80	1.07	1.19	1.45	1.68	1.64	1.85	2.28	2.33	ns	
SSTL18_I_F	0.67	0.75	0.82	0.87	1.12	1.24	1.49	1.72	1.69	1.90	2.32	2.37	ns	
SSTL18_II_F	0.67	0.75	0.82	0.87	1.12	1.24	1.49	1.71	1.69	1.90	2.32	2.36	ns	
DIFF_SSTL135_F	0.68	0.76	0.83	0.87	1.12	1.24	1.49	1.71	1.69	1.90	2.32	2.36	ns	
DIFF_SSTL15_F	0.68	0.76	0.83	0.87	1.07	1.19	1.45	1.68	1.64	1.85	2.28	2.33	ns	
DIFF_SSTL18_I_F	0.71	0.79	0.86	0.87	1.23	1.35	1.60	1.80	1.79	2.01	2.43	2.45	ns	
DIFF_SSTL18_II_F	0.71	0.79	0.86	0.87	1.21	1.33	1.59	1.79	1.78	1.99	2.42	2.44	ns	

Table 17 specifies the values of T_{IOTPHZ} and T_{IOIBUFDISABLE}. T_{IOTPHZ} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is enabled (i.e., a high impedance state). T_{IOIBUFDISABLE} is described as the IOB delay from IBUFDISABLE to O output. In HR I/O banks, the internal IN_TERM termination turn-off time is always faster than T_{IOTPHZ} when the INTERMDISABLE pin is used.

Table 17: IOB 3-state Output Switching Characteristics

Symbol	Description	Speed Grade				Units	
		1.0V		0.9V			
		-3	-2/-2L	-1	-2L		
T _{IOTPHZ}	T input to pad high-impedance	2.06	2.19	2.37	2.19	ns	
T _{IOIBUFDISABLE}	IBUF turn-on time from IBUFDISABLE to O output	2.11	2.30	2.60	2.30	ns	

Input/Output Delay Switching Characteristics

Table 22: Input/Output Delay Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
IDELAYCTRL						
T _{DLYCCO_RDY}	Reset to ready for IDELAYCTRL	3.67	3.67	3.67	3.22	μs
F _{IDELAYCTRL_REF}	Attribute REFCLK frequency = 200.00 ⁽¹⁾	200.00	200.00	200.00	200.00	MHz
	Attribute REFCLK frequency = 300.00 ⁽¹⁾	300.00	300.00	N/A	N/A	MHz
IDELAYCTRL_REF_PRECISION	REFCLK precision	±10	±10	±10	±10	MHz
T _{IDELAYCTRL_RPW}	Minimum Reset pulse width	59.28	59.28	59.28	52.00	ns
IDELAY						
T _{IDELAYRESOLUTION}	IDELAY chain delay resolution	1/(32 x 2 x F _{REF})				ps
T _{IDELAYPAT_JIT}	Pattern dependent period jitter in delay chain for clock pattern. ⁽²⁾	0	0	0	0	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23) ⁽³⁾	±5	±5	±5	±5	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23) ⁽⁴⁾	±9	±9	±9	±9	ps per tap
T _{IDELAY_CLK_MAX}	Maximum frequency of CLK input to IDELAY	680.00	680.00	600.00	520.00	MHz
T _{IDCCK_CE} / T _{IDCKC_CE}	CE pin setup/hold with respect to C for IDELAY	0.12/0.11	0.16/0.13	0.21/0.16	0.14/0.16	ns
T _{IDCCK_INC} / T _{IDCKC_INC}	INC pin setup/hold with respect to C for IDELAY	0.12/0.16	0.14/0.18	0.16/0.22	0.10/0.23	ns
T _{IDCCK_RST} / T _{IDCKC_RST}	RST pin setup/hold with respect to C for IDELAY	0.15/0.09	0.16/0.11	0.18/0.14	0.22/0.19	ns
T _{IDDO_IDATAIN}	Propagation delay through IDELAY	Note 5	Note 5	Note 5	Note 5	ps

Notes:

1. Average Tap Delay at 200 MHz = 78 ps, at 300 MHz = 52 ps.
2. When HIGH_PERFORMANCE mode is set to TRUE or FALSE.
3. When HIGH_PERFORMANCE mode is set to TRUE.
4. When HIGH_PERFORMANCE mode is set to FALSE.
5. Delay depends on IDELAY tap setting. See TRACE report for actual values.

Table 23: IO_FIFO Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
IO_FIFO Clock to Out Delays						
T _{OFFCKO_DO}	RDCLK to Q outputs	0.55	0.60	0.68	0.81	ns
T _{CKO_FLAGS}	Clock to IO_FIFO flags	0.55	0.61	0.77	0.55	ns
Setup/Hold						
T _{CCK_D/T_{CKC_D}}	D inputs to WRCLK	0.47/0.02	0.51/0.02	0.58/0.02	0.76/-0.05	ns
T _{IFFCCK_WREN/T_{IFFCKC_WREN}}	WREN to WRCLK	0.42/-0.01	0.47/-0.01	0.53/-0.01	0.70/-0.05	ns
T _{OFFCCK_RDEN/T_{OFFCKC_RDEN}}	RDEN to RDCLK	0.53/0.02	0.58/0.02	0.66/0.02	0.79/-0.02	ns
Minimum Pulse Width						
T _{PWH_IO_FIFO}	RESET, RDCLK, WRCLK	1.62	2.15	2.15	2.15	ns
T _{PWL_IO_FIFO}	RESET, RDCLK, WRCLK	1.62	2.15	2.15	2.15	ns
Maximum Frequency						
F _{MAX}	RDCLK and WRCLK	266.67	200.00	200.00	200.00	MHz

CLB Switching Characteristics

Table 24: CLB Switching Characteristics

Symbol	Description	Speed Grade				Units	
		1.0V		0.9V			
		-3	-2/-2L	-1	-2L		
Combinatorial Delays							
T _{ILO}	An – Dn LUT address to A	0.10	0.11	0.13	0.15	ns, Max	
T _{ILO_2}	An – Dn LUT address to AMUX/CMUX	0.27	0.30	0.36	0.41	ns, Max	
T _{ILO_3}	An – Dn LUT address to BMUX_A	0.42	0.46	0.55	0.65	ns, Max	
T _{I TO}	An – Dn inputs to A – D Q outputs	0.94	1.05	1.27	1.51	ns, Max	
T _{AXA}	AX inputs to AMUX output	0.62	0.69	0.84	1.01	ns, Max	
T _{AXB}	AX inputs to BMUX output	0.58	0.66	0.83	0.98	ns, Max	
T _{AXC}	AX inputs to CMUX output	0.60	0.68	0.82	0.98	ns, Max	
T _{AXD}	AX inputs to DMUX output	0.68	0.75	0.90	1.08	ns, Max	
T _{BXB}	BX inputs to BMUX output	0.51	0.57	0.69	0.82	ns, Max	
T _{BXD}	BX inputs to DMUX output	0.62	0.69	0.82	0.99	ns, Max	
T _{CXC}	CX inputs to CMUX output	0.42	0.48	0.58	0.69	ns, Max	
T _{CXD}	CX inputs to DMUX output	0.53	0.59	0.71	0.86	ns, Max	
T _{DXD}	DX inputs to DMUX output	0.52	0.58	0.70	0.84	ns, Max	
Sequential Delays							
T _{CKO}	Clock to AQ – DQ outputs	0.40	0.44	0.53	0.62	ns, Max	
T _{SHCKO}	Clock to AMUX – DMUX outputs	0.47	0.53	0.66	0.73	ns, Max	
Setup and Hold Times of CLB Flip-Flops Before/After Clock CLK							
T _{AS/T_{AH}}	A _N – D _N input to CLK on A – D flip-flops	0.07/0.12	0.09/0.14	0.11/0.18	0.11/0.20	ns, Min	
T _{DICK/T_{CKDI}}	A _X – D _X input to CLK on A – D flip-flops	0.06/0.19	0.07/0.21	0.09/0.26	0.09/0.31	ns, Min	
	A _X – D _X input through MUXs and/or carry logic to CLK on A – D flip-flops	0.59/0.08	0.66/0.09	0.81/0.11	0.97/0.12	ns, Min	
T _{CECK_CLB/} T _{CKCE_CLB}	CE input to CLK on A – D flip-flops	0.15/0.00	0.17/0.00	0.21/0.01	0.34/–0.01	ns, Min	
T _{SRCK/T_{CKSR}}	SR input to CLK on A – D flip-flops	0.38/0.03	0.43/0.04	0.53/0.05	0.62/0.05	ns, Min	
Set/Reset							
T _{SRMIN}	SR input minimum pulse width	0.52	0.78	1.04	0.95	ns, Min	
T _{RQ}	Delay from SR input to AQ – DQ flip-flops	0.53	0.59	0.71	0.83	ns, Max	
T _{CEO}	Delay from CE input to AQ – DQ flip-flops	0.52	0.58	0.70	0.83	ns, Max	
F _{TOG}	Toggle frequency (for export control)	1412	1286	1098	1098	MHz	

CLB Distributed RAM Switching Characteristics (SLICEM Only)

Table 25: CLB Distributed RAM Switching Characteristics

Symbol	Description	Speed Grade				Units	
		1.0V		0.9V			
		-3	-2/-2L	-1	-2L		
Sequential Delays							
T _{SHCKO}	Clock to A – B outputs	0.98	1.09	1.32	1.54	ns, Max	
T _{SHCKO_1}	Clock to AMUX – BMUX outputs	1.37	1.53	1.86	2.18	ns, Max	
Setup and Hold Times Before/After Clock CLK							
T _{DS_LRAM} /T _{DH_LRAM}	A – D inputs to CLK	0.54/0.28	0.60/0.30	0.72/0.35	0.96/0.40	ns, Min	
T _{AS_LRAM} /T _{AH_LRAM}	Address An inputs to clock	0.27/0.55	0.30/0.60	0.37/0.70	0.43/0.71	ns, Min	
	Address An inputs through MUXs and/or carry logic to clock	0.69/0.18	0.77/0.21	0.94/0.26	1.11/0.29	ns, Min	
T _{WS_LRAM} /T _{WH_LRAM}	WE input to clock	0.38/0.10	0.43/0.12	0.53/0.17	0.62/0.13	ns, Min	
T _{CECK_LRAM} / T _{CKCE_LRAM}	CE input to CLK	0.39/0.10	0.44/0.11	0.53/0.17	0.63/0.12	ns, Min	
Clock CLK							
T _{MPW_LRAM}	Minimum pulse width	1.05	1.13	1.25	0.82	ns, Min	
T _{MCP}	Minimum clock period	2.10	2.26	2.50	1.64	ns, Min	

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time.
2. T_{SHCKO} also represents the CLK to XMUX output. Refer to TRACE report for the CLK to XMUX path.

CLB Shift Register Switching Characteristics (SLICEM Only)

Table 26: CLB Shift Register Switching Characteristics

Symbol	Description	Speed Grade				Units	
		1.0V		0.9V			
		-3	-2/-2L	-1	-2L		
Sequential Delays							
T _{REG}	Clock to A – D outputs	1.19	1.33	1.61	1.89	ns, Max	
T _{REG_MUX}	Clock to AMUX – DMUX output	1.58	1.77	2.15	2.53	ns, Max	
T _{REG_M31}	Clock to DMUX output via M31 output	1.12	1.23	1.46	1.68	ns, Max	
Setup and Hold Times Before/After Clock CLK							
T _{WS_SHFREG} / T _{WH_SHFREG}	WE input	0.37/0.10	0.41/0.12	0.51/0.17	0.59/0.13	ns, Min	
T _{CECK_SHFREG} / T _{CKCE_SHFREG}	CE input to CLK	0.37/0.10	0.42/0.11	0.52/0.17	0.60/0.12	ns, Min	
T _{DS_SHFREG} / T _{DH_SHFREG}	A – D inputs to CLK	0.33/0.34	0.37/0.37	0.44/0.43	0.54/0.47	ns, Min	
Clock CLK							
T _{MPW_SHFREG}	Minimum pulse width	0.77	0.86	0.98	1.04	ns, Min	

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time.

Block RAM and FIFO Switching Characteristics

Table 27: Block RAM and FIFO Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
Block RAM and FIFO Clock-to-Out Delays						
T _{RCKO_DO} and T _{RCKO_DO_REG} ⁽¹⁾	Clock CLK to DOUT output (without output register) ⁽²⁾⁽³⁾	1.85	2.13	2.46	2.87	ns, Max
	Clock CLK to DOUT output (with output register) ⁽⁴⁾⁽⁵⁾	0.64	0.74	0.89	1.02	ns, Max
T _{RCKO_DO_ECC} and T _{RCKO_DO_ECC_REG}	Clock CLK to DOUT output with ECC (without output register) ⁽²⁾⁽³⁾	2.77	3.04	3.84	5.30	ns, Max
	Clock CLK to DOUT output with ECC (with output register) ⁽⁴⁾⁽⁵⁾	0.73	0.81	0.94	1.11	ns, Max
T _{RCKO_DO_CASCOUP} and T _{RCKO_DO_CASCOUP_REG}	Clock CLK to DOUT output with cascade (without output register) ⁽²⁾	2.61	2.88	3.30	3.76	ns, Max
	Clock CLK to DOUT output with cascade (with output register) ⁽⁴⁾	1.16	1.28	1.46	1.56	ns, Max
T _{RCKO_FLAGS}	Clock CLK to FIFO flags outputs ⁽⁶⁾	0.76	0.87	1.05	1.14	ns, Max
T _{RCKO_POINTERS}	Clock CLK to FIFO pointers outputs ⁽⁷⁾	0.94	1.02	1.15	1.30	ns, Max
T _{RCKO_PARITY_ECC}	Clock CLK to ECCPARITY in ECC encode only mode	0.78	0.85	0.94	1.10	ns, Max
T _{RCKO_SDBIT_ECC} and T _{RCKO_SDBIT_ECC_REG}	Clock CLK to BITERR (without output register)	2.56	2.81	3.55	4.90	ns, Max
	Clock CLK to BITERR (with output register)	0.68	0.76	0.89	1.05	ns, Max
T _{RCKO_RDADDR_ECC} and T _{RCKO_RDADDR_ECC_REG}	Clock CLK to RDADDR output with ECC (without output register)	0.75	0.88	1.07	1.15	ns, Max
	Clock CLK to RDADDR output with ECC (with output register)	0.84	0.93	1.08	1.29	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{RCKC_ADDRA} /T _{RCKC_ADDRA}	ADDR inputs ⁽⁸⁾	0.45/0.31	0.49/0.33	0.57/0.36	0.77/0.45	ns, Min
T _{RDCK_DI_WF_NC} /T _{RCKD_DI_WF_NC}	Data input setup/hold time when block RAM is configured in WRITE_FIRST or NO_CHANGE mode ⁽⁹⁾	0.58/0.60	0.65/0.63	0.74/0.67	0.92/0.76	ns, Min
T _{RDCK_DI_RF} /T _{RCKD_DI_RF}	Data input setup/hold time when block RAM is configured in READ_FIRST mode ⁽⁹⁾	0.20/0.29	0.22/0.34	0.25/0.41	0.29/0.38	ns, Min
T _{RDCK_DI_ECC} /T _{RCKD_DI_ECC}	DIN inputs with block RAM ECC in standard mode ⁽⁹⁾	0.50/0.43	0.55/0.46	0.63/0.50	0.78/0.54	ns, Min
T _{RDCK_DI_ECCW} /T _{RCKD_DI_ECCW}	DIN inputs with block RAM ECC encode only ⁽⁹⁾	0.93/0.43	1.02/0.46	1.17/0.50	1.38/0.48	ns, Min
T _{RDCK_DI_ECC_FIFO} /T _{RCKD_DI_ECC_FIFO}	DIN inputs with FIFO ECC in standard mode ⁽⁹⁾	1.04/0.56	1.15/0.59	1.32/0.64	1.55/0.77	ns, Min
T _{RCKC_INJECTBITERR} /T _{RCKC_INJECTBITERR}	Inject single/double bit error in ECC mode	0.58/0.35	0.64/0.37	0.74/0.40	0.92/0.48	ns, Min
T _{RCKC_EN} /T _{RCKC_EN}	Block RAM enable (EN) input	0.35/0.20	0.39/0.21	0.45/0.23	0.57/0.26	ns, Min
T _{RCKC_REGCE} /T _{RCKC_REGCE}	CE input of output register	0.24/0.15	0.29/0.15	0.36/0.16	0.40/0.19	ns, Min
T _{RCKC_RSTREG} /T _{RCKC_RSTREG}	Synchronous RSTREG input	0.29/0.07	0.32/0.07	0.35/0.07	0.41/0.07	ns, Min

Table 27: Block RAM and FIFO Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
T _{RCKC_RSTRAM} /T _{RCKC_RSTRAM}	Synchronous RSTRAM input	0.32/0.42	0.34/0.43	0.36/0.46	0.40/0.47	ns, Min
T _{RCKC_WEA} /T _{RCKC_WEA}	Write enable (WE) input (block RAM only)	0.44/0.18	0.48/0.19	0.54/0.20	0.64/0.23	ns, Min
T _{RCKC_WREN} /T _{RCKC_WREN}	WREN FIFO inputs	0.46/0.30	0.46/0.35	0.47/0.43	0.77/0.44	ns, Min
T _{RCKC_RDEN} /T _{RCKC_RDEN}	RDEN FIFO inputs	0.42/0.30	0.43/0.35	0.43/0.43	0.71/0.44	ns, Min
Reset Delays						
T _{RCO_FLAGS}	Reset RST to FIFO flags/pointers ⁽¹⁰⁾	0.90	0.98	1.10	1.25	ns, Max
T _{RREC_RST} /T _{RREM_RST}	FIFO reset recovery and removal timing ⁽¹¹⁾	1.87/-0.81	2.07/-0.81	2.37/-0.81	2.44/-0.71	ns, Max
Maximum Frequency						
F _{MAX_BRAM_WF_NC}	Block RAM (write first and no change modes) when not in SDP RF mode	509.68	460.83	388.20	315.66	MHz
F _{MAX_BRAM_RF_PERFORMANCE}	Block RAM (read first, performance mode) when in SDP RF mode but no address overlap between port A and port B	509.68	460.83	388.20	315.66	MHz
F _{MAX_BRAM_RF_DELAYED_WRITE}	Block RAM (read first, delayed write mode) when in SDP RF mode and there is possibility of overlap between port A and port B addresses	447.63	404.53	339.67	268.96	MHz
F _{MAX_CAS_WF_NC}	Block RAM cascade (write first, no change mode) when cascade but not in RF mode	467.07	418.59	345.78	273.30	MHz
F _{MAX_CAS_RF_PERFORMANCE}	Block RAM cascade (read first, performance mode) when in cascade with RF mode and no possibility of address overlap/one port is disabled	467.07	418.59	345.78	273.30	MHz
F _{MAX_CAS_RF_DELAYED_WRITE}	When in cascade RF mode and there is a possibility of address overlap between port A and port B	405.35	362.19	297.35	226.60	MHz
F _{MAX_FIFO}	FIFO in all modes without ECC	509.68	460.83	388.20	315.66	MHz
F _{MAX_ECC}	Block RAM and FIFO in ECC configuration	410.34	365.10	297.53	215.38	MHz

Notes:

1. TRACE will report all of these parameters as T_{RCKO_DO}.
2. T_{RCKO_DOR} includes T_{RCKO_DOW}, T_{RCKO_DOPR}, and T_{RCKO_DOPW} as well as the B port equivalent timing parameters.
3. These parameters also apply to synchronous FIFO with DO_REG = 0.
4. T_{RCKO_DO} includes T_{RCKO_DOP} as well as the B port equivalent timing parameters.
5. These parameters also apply to multirate (asynchronous) and synchronous FIFO with DO_REG = 1.
6. T_{RCKO_FLAGS} includes the following parameters: T_{RCKO_AEMPTY}, T_{RCKO_AFULL}, T_{RCKO_EMPTY}, T_{RCKO_FULL}, T_{RCKO_RDERR}, T_{RCKO_WRERR}.
7. T_{RCKO_POINTERS} includes both T_{RCKO_RDCOUNT} and T_{RCKO_WRCOUNT}.
8. The ADDR setup and hold must be met when EN is asserted (even when WE is deasserted). Otherwise, block RAM data corruption is possible.
9. These parameters include both A and B inputs as well as the parity inputs of A and B.
10. T_{RCO_FLAGS} includes the following flags: AEMPTY, AFULL, EMPTY, FULL, RDERR, WRERR, RDCOUNT, and WRCOUNT.
11. RDEN and WREN must be held Low prior to and during reset. The FIFO reset must be asserted for at least five positive clock edges of the slowest clock (WRCLK or RDCLK).

Table 28: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
Setup and Hold Times of the RST Pins						
$T_{DSPDCK_RSTA; RSTB_AREG; BREG}/T_{DSPCKD_RSTA; RSTB_AREG; BREG}$	{RSTA, RSTB} input to {A, B} register CLK	0.41/ 0.11	0.46/ 0.13	0.55/ 0.15	0.63/ 0.40	ns
$T_{DSPDCK_RSTC_CREG}/T_{DSPCKD_RSTC_CREG}$	RSTC input to C register CLK	0.07/ 0.10	0.08/ 0.11	0.09/ 0.12	0.13/ 0.11	ns
$T_{DSPDCK_RSTD_DREG}/T_{DSPCKD_RSTD_DREG}$	RSTD input to D register CLK	0.44/ 0.07	0.50/ 0.08	0.59/ 0.09	0.67/ 0.08	ns
$T_{DSPDCK_RSTM_MREG}/T_{DSPCKD_RSTM_MREG}$	RSTM input to M register CLK	0.21/ 0.22	0.23/ 0.24	0.27/ 0.28	0.28/ 0.35	ns
$T_{DSPDCK_RSTP_PREG}/T_{DSPCKD_RSTP_PREG}$	RSTP input to P register CLK	0.27/ 0.01	0.30/ 0.01	0.35/ 0.01	0.43/ 0.00	ns
Combinatorial Delays from Input Pins to Output Pins						
$T_{DSPDO_A_CARRYOUT_MULT}$	A input to CARRYOUT output using multiplier	3.79	4.35	5.18	6.61	ns
$T_{DSPDO_D_P_MULT}$	D input to P output using multiplier	3.72	4.26	5.07	6.41	ns
$T_{DSPDO_B_P}$	B input to P output not using multiplier	1.53	1.75	2.08	2.48	ns
$T_{DSPDO_C_P}$	C input to P output	1.33	1.53	1.82	2.22	ns
Combinatorial Delays from Input Pins to Cascading Output Pins						
$T_{DSPDO_A; B}_ACOUT; BCOUT}$	{A, B} input to {ACOUT, BCOUT} output	0.55	0.63	0.74	0.87	ns
$T_{DSPDO_A, B}_CARRYCASOUT_MULT}$	{A, B} input to CARRYCASOUT output using multiplier	4.06	4.65	5.54	7.03	ns
$T_{DSPDO_D}_CARRYCASOUT_MULT$	D input to CARRYCASOUT output using multiplier	3.97	4.54	5.40	6.81	ns
$T_{DSPDO_A, B}_CARRYCASOUT$	{A, B} input to CARRYCASOUT output not using multiplier	1.77	2.03	2.41	2.88	ns
$T_{DSPDO_C}_CARRYCASOUT$	C input to CARRYCASOUT output	1.58	1.81	2.15	2.62	ns
Combinatorial Delays from Cascading Input Pins to All Output Pins						
$T_{DSPDO_ACIN_P_MULT}$	ACIN input to P output using multiplier	3.65	4.19	5.00	6.40	ns
$T_{DSPDO_ACIN_P}$	ACIN input to P output not using multiplier	1.37	1.57	1.88	2.44	ns
$T_{DSPDO_ACIN_ACOUT}$	ACIN input to ACOUT output	0.38	0.44	0.53	0.63	ns
$T_{DSPDO_ACIN}_CARRYCASOUT_MULT$	ACIN input to CARRYCASOUT output using multiplier	3.90	4.47	5.33	6.79	ns
$T_{DSPDO_ACIN}_CARRYCASOUT$	ACIN input to CARRYCASOUT output not using multiplier	1.61	1.85	2.21	2.84	ns
$T_{DSPDO_PCIN_P}$	PCIN input to P output	1.11	1.28	1.52	1.82	ns
$T_{DSPDO_PCIN}_CARRYCASOUT$	PCIN input to CARRYCASOUT output	1.36	1.56	1.85	2.21	ns
Clock to Outs from Output Register Clock to Output Pins						
$T_{DSPCKO_P_PREG}$	CLK PREG to P output	0.33	0.37	0.44	0.54	ns
$T_{DSPCKO}_CARRYCASOUT_PREG$	CLK PREG to CARRYCASOUT output	0.52	0.59	0.69	0.84	ns

Clock Buffers and Networks

Table 29: Global Clock Switching Characteristics (Including BUFGCTRL)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
T_BCCCK_CE/T_BCCKC_CE ⁽¹⁾	CE pins setup/hold	0.12/0.39	0.13/0.40	0.16/0.41	0.31/0.17	ns
T_BCCCK_S/T_BCCKC_S ⁽¹⁾	S pins setup/hold	0.12/0.39	0.13/0.40	0.16/0.41	0.31/0.17	ns
T_BGCKO_O ⁽²⁾	BUFGCTRL delay from I0/I1 to O	0.08	0.09	0.10	0.14	ns
Maximum Frequency						
F _{MAX_BUFG}	Global clock tree (BUFG)	628.00	628.00	464.00	394.00	MHz

Notes:

1. T_{BCCCK_CE} and T_{BCCKC_CE} must be satisfied to assure glitch-free operation of the global clock when switching between clocks. These parameters do not apply to the BUFGMUX primitive that assures glitch-free operation. The other global clock setup and hold times are optional; only needing to be satisfied if device operation requires simulation matches on a cycle-for-cycle basis when switching between clocks.
2. T_{BGCKO_O} (BUFG delay from I0 to O) values are the same as T_{BCCKO_O} values.

Table 30: Input/Output Clock Switching Characteristics (BUFIO)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
T_BLOCKO_O	Clock to out delay from I to O	1.11	1.26	1.54	1.56	ns
Maximum Frequency						
F _{MAX_BUFIO}	I/O clock tree (BUFIO)	680.00	680.00	600.00	600.00	MHz

Table 31: Regional Clock Buffer Switching Characteristics (BUFR)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
T_BRCKO_O	Clock to out delay from I to O	0.64	0.76	0.99	1.24	ns
T_BRCKO_O_BYP	Clock to out delay from I to O with Divide Bypass attribute set	0.34	0.39	0.52	0.72	ns
T_BRDO_O	Propagation delay from CLR to O	0.81	0.85	1.09	0.96	ns
Maximum Frequency						
F _{MAX_BUFR} ⁽¹⁾	Regional clock tree (BUFR)	420.00	375.00	315.00	315.00	MHz

Notes:

1. The maximum input frequency to the BUFR and BUFMR is the BUFIO F_{MAX} frequency.

PLL Switching Characteristics

Table 35: PLL Specification

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
PLL_F _{INMAX}	Maximum input clock frequency	800.00	800.00	800.00	800.00	MHz
PLL_F _{INMIN}	Minimum input clock frequency	19.00	19.00	19.00	19.00	MHz
PLL_F _{INJITTER}	Maximum input clock period jitter	< 20% of clock input period or 1 ns Max				
PLL_F _{INDUTY}	Allowable input duty cycle: 19—49 MHz	25	25	25	25	%
	Allowable input duty cycle: 50—199 MHz	30	30	30	30	%
	Allowable input duty cycle: 200—399 MHz	35	35	35	35	%
	Allowable input duty cycle: 400—499 MHz	40	40	40	40	%
	Allowable input duty cycle: >500 MHz	45	45	45	45	%
PLL_F _{VCOMIN}	Minimum PLL VCO frequency	800.00	800.00	800.00	800.00	MHz
PLL_F _{VCOMAX}	Maximum PLL VCO frequency	2133.00	1866.00	1600.00	1600.00	MHz
PLL_F _{BANDWIDTH}	Low PLL bandwidth at typical ⁽¹⁾	1.00	1.00	1.00	1.00	MHz
	High PLL bandwidth at typical ⁽¹⁾	4.00	4.00	4.00	4.00	MHz
PLL_T _{STATPHAOFFSET}	Static phase offset of the PLL outputs ⁽²⁾	0.12	0.12	0.12	0.12	ns
PLL_T _{OUTJITTER}	PLL output jitter	Note 3				
PLL_T _{OUTDUTY}	PLL output clock duty-cycle precision ⁽⁴⁾	0.20	0.20	0.20	0.25	ns
PLL_T _{LOCKMAX}	PLL maximum lock time	100.00	100.00	100.00	100.00	μs
PLL_F _{OUTMAX}	PLL maximum output frequency	800.00	800.00	800.00	800.00	MHz
PLL_F _{OUTMIN}	PLL minimum output frequency ⁽⁵⁾	6.25	6.25	6.25	6.25	MHz
PLL_T _{EXTFDVAR}	External clock feedback variation	< 20% of clock input period or 1 ns Max				
PLL_RST _{MINPULSE}	Minimum reset pulse width	5.00	5.00	5.00	5.00	ns
PLL_F _{PFDMAX}	Maximum frequency at the phase frequency detector	550.00	500.00	450.00	450.00	MHz
PLL_F _{PFDMIN}	Minimum frequency at the phase frequency detector	19.00	19.00	19.00	19.00	MHz
PLL_T _{FBDELAY}	Maximum delay in the feedback path	3 ns Max or one CLKIN cycle				

Dynamic Reconfiguration Port (DRP) for PLL Before and After DCLK

T _{PLLDCK_DADDR} /T _{PLLCKD_DADDR}	Setup and hold of D address	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T _{PLLDCK_DI} /T _{PLLCKD_DI}	Setup and hold of D input	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T _{PLLDCK_DEN} /T _{PLLCKD_DEN}	Setup and hold of D enable	1.76/0.00	1.97/0.00	2.29/0.00	2.40/0.00	ns, Min
T _{PLLDCK_DWE} /T _{PLLCKD_DWE}	Setup and hold of D write enable	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
T _{PLLCKO_DRDY}	CLK to out of DRDY	0.65	0.72	0.99	0.99	ns, Max
F _{DCK}	DCLK frequency	200.00	200.00	200.00	100.00	MHz, Max

Notes:

1. The PLL does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
2. The static offset is measured between any PLL outputs with identical phase.
3. Values for this parameter are available in the Clocking Wizard.
See http://www.xilinx.com/products/intellectual-property/clocking_wizard.htm.
4. Includes global clock buffer.
5. Calculated as F_{VCO}/128 assuming output duty cycle is 50%.

Table 44: Data Input Setup and Hold Times Relative to a Forwarded Clock Input Pin Using BUFIO

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
Input Setup and Hold Time Relative to a Forwarded Clock Input Pin Using BUFIO for SSTL15 Standard.						
T _{PSCS} /T _{PHCS}	Setup and hold of I/O clock	-0.38/1.31	-0.38/1.46	-0.38/1.76	-0.16/1.89	ns

Table 45: Sample Window

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
T _{SAMP}	Sampling error at receiver pins ⁽¹⁾	0.59	0.64	0.70	0.70	ns
T _{SAMP_BUFI0}	Sampling error at receiver pins using BUFIO ⁽²⁾	0.35	0.40	0.46	0.46	ns

Notes:

1. This parameter indicates the total sampling error of the Artix-7 FPGAs DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the MMCM to capture the DDR input registers' edges of operation. These measurements include:
 - CLKO MMCM jitter
 - MMCM accuracy (phase offset)
 - MMCM phase shift resolution
 These measurements do not include package or clock tree skew.
2. This parameter indicates the total sampling error of the Artix-7 FPGAs DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the BUFIO clock network and IDELAY to capture the DDR input registers' edges of operation. These measurements do not include package or clock tree skew.

Additional Package Parameter Guidelines

The parameters in this section provide the necessary values for calculating timing budgets for Artix-7 FPGA clock transmitter and receiver data-valid windows.

Table 46: Package Skew

Symbol	Description	Device	Package	Value	Units
T _{PKGSKEW}	Package skew ⁽¹⁾	XC7A100T	CSG324	113	ps
			FTG256	120	ps
			FGG484	144	ps
			FGG676	153	ps
		XC7A200T	SBG484	111	ps
			FBG484	109	ps
			FBG676	121	ps
			FFG1156	151	ps

Notes:

1. These values represent the worst-case skew between any two SelectIO resources in the package: shortest delay to longest delay from die pad to ball.
2. Package delay information is available for these device/package combinations. This information can be used to deskew the package.

GTP Transceiver Specifications

GTP Transceiver DC Input and Output Levels

Table 47 summarizes the DC output specifications of the GTP transceivers in Artix-7 FPGAs. Consult [UG482: 7 Series FPGAs GTP Transceiver User Guide](#) for further details.

Table 47: GTP Transceiver DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
DV_{PPOUT}	Differential peak-to-peak output voltage ⁽¹⁾	Transmitter output swing is set to maximum setting	—	—	1000	mV
$V_{CMOUTDC}$	DC common mode output voltage	Equation based	$V_{MGTAVTT} - DV_{PPOUT}/4$			mV
R_{OUT}	Differential output resistance		—	100	—	Ω
$V_{CMOUTAC}$	Common mode output voltage: AC coupled		$1/2 V_{MGTAVTT}$			mV
T_{OSKEW}	Transmitter output pair (TXP and TXN) intra-pair skew (FFG, FBG, SBG packages)		—	—	10	ps
	Transmitter output pair (TXP and TXN) intra-pair skew (FGG, FTG, CSG packages)		—	—	12	ps
DV_{PPIN}	Differential peak-to-peak input voltage	External AC coupled	150	—	2000	mV
V_{IN}	Absolute input voltage	DC coupled $V_{MGTAVTT} = 1.2V$	-200	—	$V_{MGTAVTT}$	mV
V_{CMIN}	Common mode input voltage	DC coupled $V_{MGTAVTT} = 1.2V$	—	$2/3 V_{MGTAVTT}$	—	mV
R_{IN}	Differential input resistance		—	100	—	Ω
C_{EXT}	Recommended external AC coupling capacitor ⁽²⁾		—	100	—	nF

Notes:

- The output swing and preemphasis levels are programmable using the attributes discussed in [UG482: 7 Series FPGAs GTP Transceiver User Guide](#) and can result in values lower than reported in this table.
- Other values can be used as appropriate to conform to specific protocols and standards.

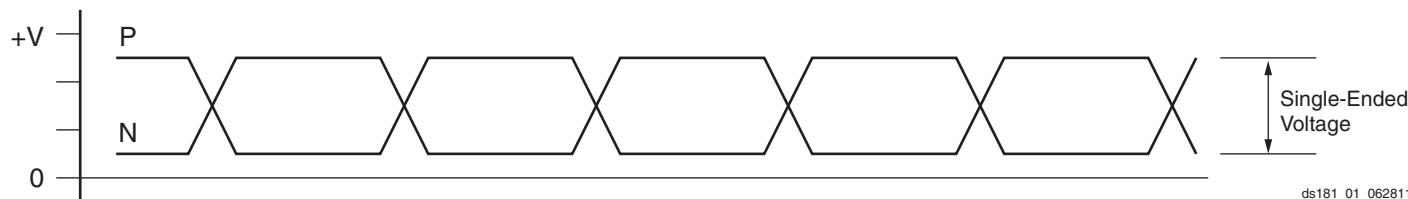


Figure 1: Single-Ended Peak-to-Peak Voltage

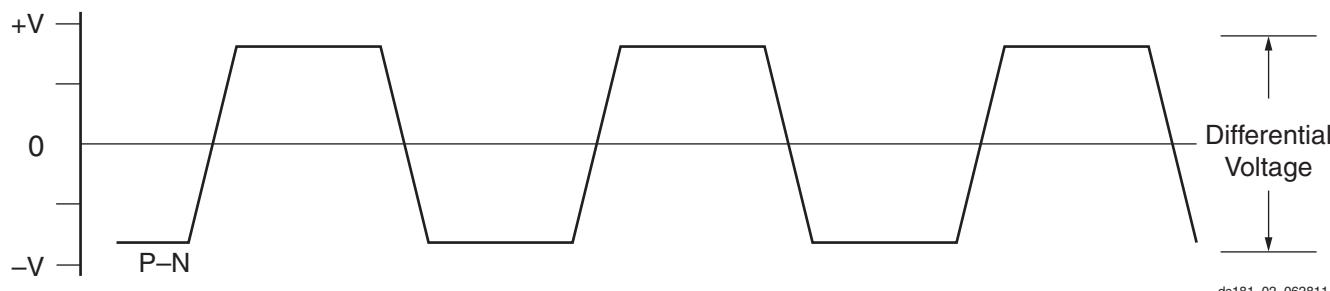


Figure 2: Differential Peak-to-Peak Voltage

Table 48 summarizes the DC specifications of the clock input of the GTP transceiver. Consult [UG482: 7 Series FPGAs GTP Transceiver User Guide](#) for further details.

Table 48: GTP Transceiver Clock DC Input Level Specification

Symbol	DC Parameter	Min	Typ	Max	Units
V_{IDIFF}	Differential peak-to-peak input voltage	350	—	2000	mV
R_{IN}	Differential input resistance	—	100	—	Ω
C_{EXT}	Required external AC coupling capacitor	—	100	—	nF

GTP Transceiver Switching Characteristics

Consult [UG482: 7 Series FPGAs GTP Transceiver User Guide](#) for further information.

Table 49: GTP Transceiver Performance

Symbol	Description	Output Divider	Speed Grade								Units	
			1.0V				0.9V					
			-3		-2/-2L		-1		-2L			
			Package Type									
			FFG FBG SBG	FGG FTG CSG	FFG FBG SBG	FGG FTG CSG	FFG FBG SBG	FGG FTG CSG	FFG FBG SBG	FGG FTG CSG		
F_{GTPMAX}	Maximum GTP transceiver data rate		6.6	5.4	6.6	5.4	3.75	3.75	3.75	3.75	Gb/s	
F_{GTPMIN}	Minimum GTP transceiver data rate		0.500	0.500	0.500	0.500	0.500	0.500	0.500	0.500	Gb/s	
$F_{GTPRANGE}$	PLL line rate range	1	3.2–6.6		3.2–6.6		3.2–3.75		3.2–3.75		Gb/s	
		2	1.6–3.3		1.6–3.3		1.6–3.2		1.6–3.2		Gb/s	
		4	0.8–1.65		0.8–1.65		0.8–1.6		0.8–1.6		Gb/s	
		8	0.5–0.825		0.5–0.825		0.5–0.8		0.5–0.8		Gb/s	
$F_{GTPPLL RANGE}$	GTP transceiver PLL frequency range		1.6–3.3		1.6–3.3		1.6–3.3		1.6–3.3		GHz	

Table 50: GTP Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics

Symbol	Description	Speed Grade				Units	
		1.0V		0.9V			
		-3	-2/-2L	-1	-2L		
$F_{GTPDRPCLK}$	GTPDRPCLK maximum frequency	175	175	156	125	MHz	

Table 51: GTP Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequency range		60	—	660	MHz
T_{RCLK}	Reference clock rise time	20% – 80%	—	200	—	ps
T_{FCLK}	Reference clock fall time	20% – 80%	—	200	—	ps
T_{DCREF}	Reference clock duty cycle	Transceiver PLL only	40	—	60	%

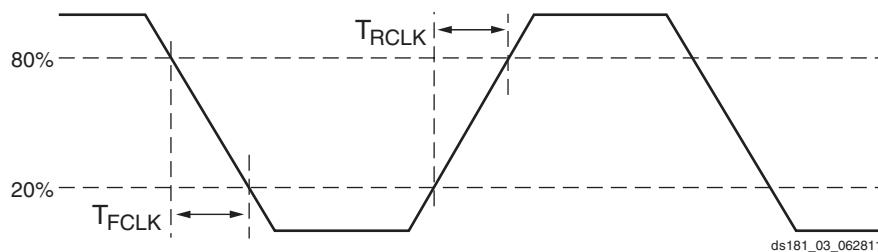


Figure 3: Reference Clock Timing Parameters

Table 52: GTP Transceiver PLL/Lock Time Adaptation

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
T _{LOCK}	Initial PLL lock		—	—	1	ms
T _{DLOCK}	Clock recovery phase acquisition and adaptation time.	After the PLL is locked to the reference clock, this is the time it takes to lock the clock data recovery (CDR) to the data present at the input.	—	50,000	2.3 x 10 ⁶	UI

Table 53: GTP Transceiver User Clock Switching Characteristics⁽¹⁾

Symbol	Description	Conditions	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
F _{TXOUT}	TXOUTCLK maximum frequency		412.500	412.500	234.375	234.375	MHz
F _{RXOUT}	RXOUTCLK maximum frequency		412.500	412.500	234.375	234.375	MHz
F _{TXIN}	TXUSRCLK maximum frequency	16-bit data path	412.500	412.500	234.375	234.375	MHz
F _{RXIN}	RXUSRCLK maximum frequency	16-bit data path	412.500	412.500	234.375	234.375	MHz
F _{TXIN2}	TXUSRCLK2 maximum frequency	16-bit data path	412.500	412.500	234.375	234.375	MHz
F _{RXIN2}	RXUSRCLK2 maximum frequency	16-bit data path	412.500	412.500	234.375	234.375	MHz

Notes:

1. Clocking must be implemented as described in [UG482: 7 Series FPGAs GTP Transceiver User Guide](#).

GTP Transceiver Protocol Jitter Characteristics

For Table 56 through Table 60, the [UG482: 7 Series FPGAs GTP Transceiver User Guide](#) contains recommended settings for optimal usage of protocol specific characteristics.

Table 56: Gigabit Ethernet Protocol Characteristics

Description	Line Rate (Mb/s)	Min	Max	Units
Gigabit Ethernet Transmitter Jitter Generation				
Total transmitter jitter (T_TJ)	1250	–	0.24	UI
Gigabit Ethernet Receiver High Frequency Jitter Tolerance				
Total receiver jitter tolerance	1250	0.749	–	UI

Table 57: XAUI Protocol Characteristics

Description	Line Rate (Mb/s)	Min	Max	Units
XAUI Transmitter Jitter Generation				
Total transmitter jitter (T_TJ)	3125	–	0.35	UI
XAUI Receiver High Frequency Jitter Tolerance				
Total receiver jitter tolerance	3125	0.65	–	UI

Table 58: PCI Express Protocol Characteristics⁽¹⁾

Standard	Description	Line Rate (Mb/s)	Min	Max	Units
PCI Express Transmitter Jitter Generation					
PCI Express Gen 1	Total transmitter jitter	2500	–	0.25	UI
PCI Express Gen 2	Total transmitter jitter	5000	–	0.25	UI
PCI Express Receiver High Frequency Jitter Tolerance					
PCI Express Gen 1	Total receiver jitter tolerance	2500	0.65	–	UI
PCI Express Gen 2 ⁽²⁾	Receiver inherent timing error	5000	0.40	–	UI
	Receiver inherent deterministic timing error		0.30	–	UI

Notes:

1. Tested per card electromechanical (CEM) methodology.
2. Using common REFCLK.

Table 59: CEI-6G Protocol Characteristics

Description	Line Rate (Mb/s)	Interface	Min	Max	Units
CEI-6G Transmitter Jitter Generation					
Total transmitter jitter ⁽¹⁾	4976–6375	CEI-6G-SR	–	0.3	UI
CEI-6G Receiver High Frequency Jitter Tolerance					
Total receiver jitter tolerance ⁽¹⁾	4976–6375	CEI-6G-SR	0.6	–	UI

Notes:

1. Tested at most commonly used line rate of 6250 Mb/s using 390.625 MHz reference clock.

Table 60: CPRI Protocol Characteristics

Description	Line Rate (Mb/s)	Min	Max	Units
CPRI Transmitter Jitter Generation				
Total transmitter jitter	614.4	–	0.35	UI
	1228.8	–	0.35	UI
	2457.6	–	0.35	UI
	3072.0	–	0.35	UI
	4915.2	–	0.3	UI
	6144.0	–	0.3	UI
CPRI Receiver Frequency Jitter Tolerance				
Total receiver jitter tolerance	614.4	0.65	–	UI
	1228.8	0.65	–	UI
	2457.6	0.65	–	UI
	3072.0	0.65	–	UI
	4915.2 ⁽¹⁾	0.60	–	UI
	6144.0 ⁽¹⁾	0.60	–	UI

Notes:

1. Tested to CEI-6G-SR.

Integrated Interface Block for PCI Express Designs Switching Characteristics

More information and documentation on solutions for PCI Express designs can be found at:

<http://www.xilinx.com/technology/protocols/pciexpress.htm>

Table 61: Maximum Performance for PCI Express Designs

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
FPIPECLK	Pipe clock maximum frequency	250.00	250.00	250.00	250.00	MHz
FUSERCLK	User clock maximum frequency	250.00	250.00	250.00	250.00	MHz
FUSERCLK2	User clock 2 maximum frequency	250.00	250.00	250.00	250.00	MHz
FRPCLK	DRP clock maximum frequency	250.00	250.00	250.00	250.00	MHz

Table 63: Configuration Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
Internal Configuration Access Port						
F _{ICAPCK}	Internal configuration access port (ICAPE2) clock frequency	100.00	100.00	100.00	70.00	MHz, Max
Master/Slave Serial Mode Programming Switching						
T _{DCCCK/T_{CCKD}}	DIN setup/hold	4.00/0.00	4.00/0.00	4.00/0.00	5.00/0.00	ns, Min
T _{CCO}	DOUT clock to out	8.00	8.00	8.00	9.00	ns, Max
SelectMAP Mode Programming Switching						
T _{SMDCCK/T_{SMCCKD}}	D[31:00] setup/hold	4.00/0.00	4.00/0.00	4.00/0.00	4.50/0.00	ns, Min
T _{SMCSCCK/T_{SMCCKCS}}	CSI_B setup/hold	4.00/0.00	4.00/0.00	4.00/0.00	5.00/0.00	ns, Min
T _{SMWCCK/T_{SMCCKW}}	RDWR_B setup/hold	10.00/0.00	10.00/0.00	10.00/0.00	12.00/0.00	ns, Min
T _{SMCKCSO}	CSO_B clock to out (330 Ω pull-up resistor required)	7.00	7.00	7.00	8.00	ns, Max
T _{SMCO}	D[31:00] clock to out in readback	8.00	8.00	8.00	10.00	ns, Max
F _{RBCCK}	Readback frequency	100.00	100.00	100.00	70.00	MHz, Max
Boundary-Scan Port Timing Specifications						
T _{TAPTCK/T_{TCKTAP}}	TMS and TDI setup/hold	3.00/2.00	3.00/2.00	3.00/2.00	3.00/2.00	ns, Min
T _{TCKTDO}	TCK falling edge to TDO output	7.00	7.00	7.00	8.50	ns, Max
F _{TCK}	TCK frequency	66.00	66.00	66.00	50.00	MHz, Max
BPI Flash Master Mode Programming Switching						
T _{BPICCO⁽²⁾}	A[28:00], RS[1:0], FCS_B, FOE_B, FWE_B, ADV_B clock to out	8.50	8.50	8.50	10.00	ns, Max
T _{BPIDCC/T_{BPICCD}}	D[15:00] setup/hold	4.00/0.00	4.00/0.00	4.00/0.00	4.50/0.00	ns, Min
SPI Flash Master Mode Programming Switching						
T _{SPIDCC/T_{SPICCD}}	D[03:00] setup/hold	3.00/0.00	3.00/0.00	3.00/0.00	3.00/0.00	ns, Min
T _{SPICCM}	MOSI clock to out	8.00	8.00	8.00	9.00	ns, Max
T _{SPICCFC}	FCS_B clock to out	8.00	8.00	8.00	9.00	ns, Max

Notes:

1. To support longer delays in configuration, use the design solutions described in [UG470: 7 Series FPGA Configuration User Guide](#).
2. Only during configuration, the last edge is determined by a weak pull-up/pull-down resistor in the I/O.

eFUSE Programming Conditions

Table 64 lists the programming conditions specifically for eFUSE. For more information, see [UG470: 7 Series FPGA Configuration User Guide](#).

Table 64: eFUSE Programming Conditions⁽¹⁾

Symbol	Description	Min	Typ	Max	Units
I _{FS}	V _{CCAUX} supply current	–	–	115	mA
t _j	Temperature range	15	–	125	°C

Notes:

1. The FPGA must not be configured during eFUSE programming.